

Supplementary Information: Measurement and Modeling of Short and Medium Range Order in Amorphous Ta₂O₅ Thin Films

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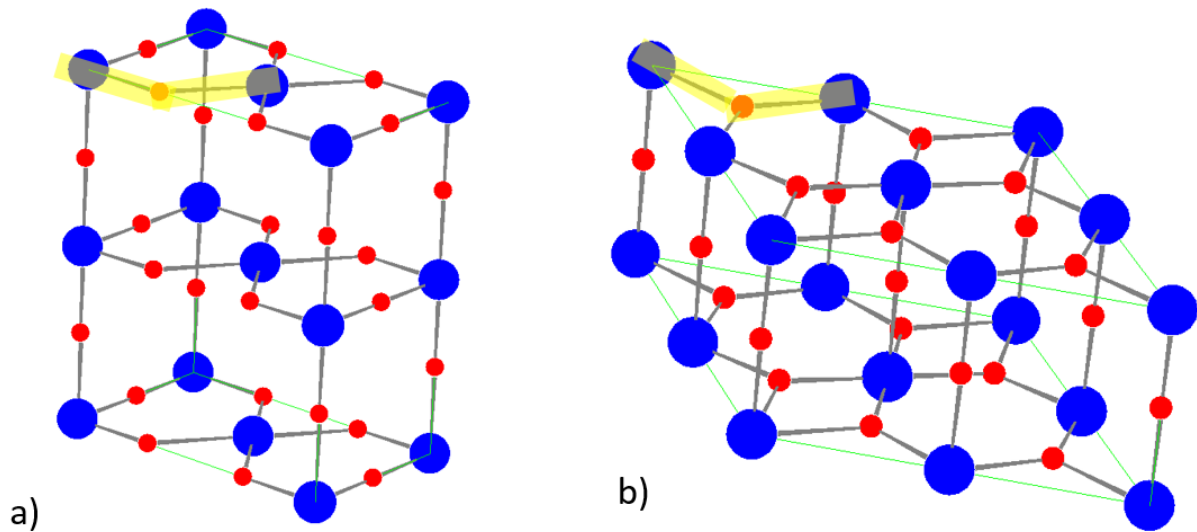


Figure 1: Schematic structure of a) β -Tantala, as reported by Aleshina and Loginova¹ b) δ -Tantala as calculated by Fukumoto and Miwa.² The blue spheres indicate Ta ions and the red sphere indicate O ions. The kinked Ta-O-Ta PSU is high-lighted in yellow.

References

1. Aleshina, L. A., & Loginova, S. V. Rietveld analysis of X-ray diffraction pattern from β -Ta₂O₅ oxide. *Crystallogr. Rep.*, **47**, 415-419 (2002).
2. Fukumoto, A., & Miwa, K. Prediction of hexagonal Ta₂O₅ structure by first-principles calculations. *Phys. Rev., B* **55**, 11155-11160 (1997).